

Search Notes

Application/Control No.

10/807,450

Examiner

John B. Nguyen

Applicant(s)/Patent under
Reexamination

NAKANO ET AL.

Art Unit

2819

SEARCHED

Class	Subclass	Date	Examiner
341	155,156	7/27/2005	JN
341	126	7/27/2005	JN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
see text serach print out	7/27/2005	JN